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| Atty. Docket No.: 3600-328-01 |  | Application No.:        | 10/042,549       |
| Applicant:                    |  | Christopher A. MICHALUK |                  |
| Filing Date: January 9, 2002  |  | Group Art Unit:         | Not Yet Assigned |

## U.S. PATENT DOCUMENTS

| Examiner Initial* |   | Document Number | Date     | Name               | Class | Sub Class | Filing Date If Appropriate |
|-------------------|---|-----------------|----------|--------------------|-------|-----------|----------------------------|
| Ato               | 1 | 2,950,185       | 08/23/60 | E.G. Helier et al. | 75    | 0.5       |                            |
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| Ato               | 8 | 6,193,821       | 02/27/01 | Zhang              | 148   | 668       |                            |
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|     |    | Document Number | Date     | Country | Class | Sub Class | Translation Yes or No |
|-----|----|-----------------|----------|---------|-------|-----------|-----------------------|
| Ato | 10 | WO 00/31310     | 06/02/00 | WIPO    |       |           | Yes                   |
|     |    |                 |          |         |       |           |                       |
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| Ato | Kirk-Othmer, Encyclopedia of Chemical Technology, 3rd Edition, Vol. 22, pp. 541-564, 1983.  |
| Ato | S.I. Wright, G.T. Gray, and A.D. Rollett, <i>Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate</i> , <u>Metallurgical and Materials Transactions A</u> , 25A, pp. 1025-1031, 1994. |
| Ato | C.A. Michaluk, R.O. Burt, and D.P. Lewis, <i>Tantalum 101: Economics and Technology of Ta Materials</i> , <u>Semiconductor International</u> , Vol. 23, No. 8, pp. 271-278, 2000.   |
| Ato | C.A. Michaluk, <i>Correlating Discrete Orientation and Grain Size to the Sputter Deposition Properties of Tantalum</i> , <u>Journal of Electronic Materials</u> , Vol. 31, No. 1, pp. 2-9, 2002.                              |
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| Examiner |  | Date Considered | 4/22/03 |
|----------|--|-----------------|---------|

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Atty. Docket No.  
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Application No. 10/042,549

## INFORMATION DISCLOSURE STATEMENT

APPLICANT: Christopher A. MICHALUK

Filing Date: January 9, 2002

Group Art Unit: 1742

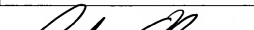
## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

|            |  | DOCUMENT<br>NUMBER | DATE     | COUNTRY | CLASS | SUB-<br>CLASS | TRANSLATION<br>YES | NO |
|------------|--|--------------------|----------|---------|-------|---------------|--------------------|----|
| <i>A10</i> |  | WO 01/96620        | 12/20/01 | WIPO    | C22B  |               |                    |    |
| <i>A10</i> |  | WO 99/61670        | 12/2/99  | WIPO    | C22B  | 34/24         |                    |    |
| <i>A10</i> |  | WO 99/66100        | 12/23/99 | WIPO    | C23C  | 14/34         |                    |    |

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| EXAMINER<br>  |  | DATE CONSIDERED<br><i>4/22/03</i> |
| <p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p> |  |                                   |